Characterisation

## METRO LAB – Micrometrology

Fundación TEKNIKER, Spain

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|---|---|---|---|---|---|---|---|
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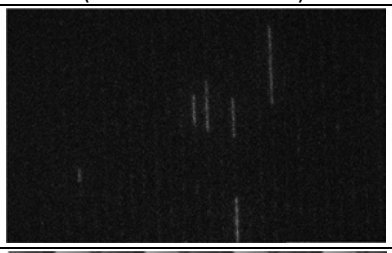
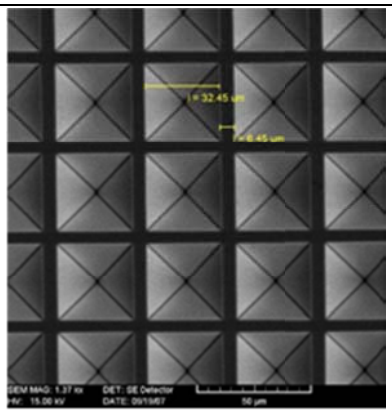
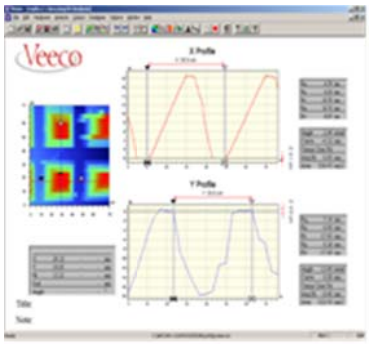
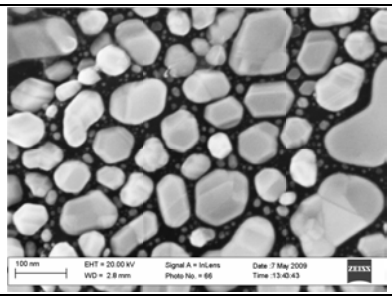
| **Material class:** | Silicon<br>X | Polymer<br>X | Metal<br>X | Ceramic<br>X | Glass<br>X | Organic | Other |
| **Short technology description:** | – Optical and fluorescent microscopy (Zeiss)<br>– Confocal microscopy<br>– Low force contact perfilometry (Veeco Dektak8)<br>– Interferometry (Veeco WYKO NT1100)<br>– FE-SEM (Zeiss Ultra Plus)<br>– AFM (NT-MDT Solver Pro) | | | | | | |
| **Typical structures and designs:** |  **Length measurements of DNA single molecules stretched in nanochannels by fluorescent microscopy** | | | | | | |
| |  **3-dimensional analysis by contact perfilomete**  | | | | | | |
| |  **AFM local anodic oxidation on a 2x1 mm Titanium surface**<br>– Height of the structures 5 nm | | | | | | |
| |  **High resolution SEM image** | | | | | | |
| **Special features:** | – Perfilometer: 3d mapping upyion<br>N-llte option: minimum force 0.03mg.<br>– SEM:EDS, EBSD,<br>– Set of Zeiss filters for fluorescent microscopy : 14 and 38HE | | | | | | |
| **Limitations, constraints:** | – Perfilometer z range 262 µm<br>– AFM z range: 5 µm | | | | | | |